



#### COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

### **Product Summary**

Device	V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub>	I <sub>D</sub> T <sub>A</sub> = 25°C
Q1	001/	0.45Ω @ V <sub>GS</sub> = 4.5V	1066mA
Q2	20V	0.75Ω @ V <sub>GS</sub> =- 4.5V	-845mA

### **Features and Benefits**

- Low On-Resistance
- Low Gate Threshold Voltage
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Complementary Pair MOSFET
- Ultra-Small Surface Mount Package
- Lead Free/RoHS Compliant (Note 1)
- ESD Protected Up to 2.5kV
- "Green" Device (Note 2)
- Qualified to AEC-Q101 Standards for High Reliabilit

#### **Description and Applications**

This new generation MOSFET has been designed to minimize the onstate resistance ( $R_{DS(on)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- Battery Operated Systems and Solid-State Relays
- Drivers: Relays, Solenoids, Lamps, Hammers, Displays, Memories, Transistors, etc.
- Power Supply Converter Circuits

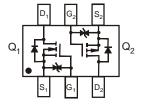
#### **Mechanical Data**

- Case: SOT-363
- Case Material: Molded Plastic, "Green" Molding Compound.
  UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Matte Tin Finish annealed over Alloy 42 leadframe (Lead Free Plating). Solderable per MIL-STD-202, Method 208
- Terminal Connections: See Diagram
- Marking Information: See Page 1
- Ordering Information: See Page 1
- Weight: 0.006 grams (approximate)





TOP VIEW



TOP VIEW Internal Schematic

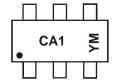
#### Ordering Information (Note 3)

Part Number	Qualification	Case	Packaging	
DMG1016UDW-7	Commercial	SOT-363	3000/Tape & Reel	
DMG1016UDWQ-7	Automotive	SOT-363	3000/Tape & Reel	

Notes:

- 1. No purposefully added lead.
- 2. Diodes Inc.'s "Green" policy can be found on our website at http://www.diodes.com.
- 3. For packaging details, go to our website at http://www.diodes.com/datasheets/ap02007.pdf

### **Marking Information**



CA1 = Product Type Marking Code YM = Date Code Marking Y = Year (ex: W = 2009) M = Month (ex: 9 = September)



# Thermal Characteristics @TA = 25°C unless otherwise specified

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 4)	P <sub>D</sub>	330	mW
Thermal Resistance, Junction to Ambient (Note 4)	$R_{ hetaJA}$	379	°C/W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C

# **Maximum Ratings N-CHANNEL – Q1** $@T_A = 25$ °C unless otherwise specified

Characteristic		Symbol	Value	Units	
Drain-Source Voltage		V <sub>DSS</sub>	20	V	
Gate-Source Voltage		V <sub>GSS</sub>	±6	V	
Continuous Drain Current (Note 4) V <sub>GS</sub> = 10V	Steady State	$T_A = 25$ °C $T_A = 85$ °C	I <sub>D</sub>	1066 690	mA

# Maximum Ratings P-CHANNEL – Q2 @TA = 25°C unless otherwise specified

Characteristic		Symbol	Value	Units	
Drain-Source Voltage		V <sub>DSS</sub>	-20	V	
Gate-Source Voltage		$V_{GSS}$	±6	V	
Continuous Drain Current (Note 4) $V_{GS} = 10V$ Steady $T_A = 25^{\circ}C$ State $T_A = 85^{\circ}C$			I <sub>D</sub>	845 548	mA

Notes: 4. Device mounted on FR-4 PCB with minimum recommended pad layout.

## Electrical Characteristics N-CHANNEL - Q1 @TA = 25°C unless otherwise specified

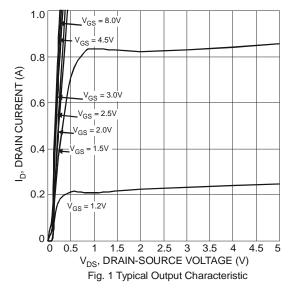
Characteristic		Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 5)		•		•	•	•	
Drain-Source Breakdown Voltage		BV <sub>DSS</sub>	20	-	-	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	@T <sub>c</sub> = 25°C	I <sub>DSS</sub>	-	-	100	nA	V <sub>DS</sub> =20V, V <sub>GS</sub> = 0V
Gate-Source Leakage		I <sub>GSS</sub>	-	-	±1.0	μΑ	$V_{GS} = \pm 4.5 V, V_{DS} = 0 V$
ON CHARACTERISTICS (Note 5)		•		•	•	•	
Gate Threshold Voltage		$V_{GS(th)}$	0.5	-	1.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
				0.3	0.45		$V_{GS} = 4.5V, I_D = 600mA$
Static Drain-Source On-Resistance		R <sub>DS (ON)</sub>	-	0.4	0.6	Ω	$V_{GS} = 2.5V, I_D = 500mA$
				0.5	0.75		$V_{GS} = 1.8V, I_D = 350mA$
Forward Transfer Admittance		Y <sub>fs</sub>	-	1.4	-	S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 400mA
Diode Forward Voltage (Note 5)		V <sub>SD</sub>	-	0.7	1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 150mA
DYNAMIC CHARACTERISTICS (Note 6)		•		•	•	•	
Input Capacitance		C <sub>iss</sub>	-	60.67	-	pF	
Output Capacitance		Coss	-	9.68	-	pF	$V_{DS} = 10V, V_{GS} = 0V,$ - f = 1.0MHz
Reverse Transfer Capacitance		C <sub>rss</sub>	-	5.37	-	pF	T = 1.0WHZ
Total Gate Charge (4.5V)		Qg	-	736.6	-	nC	
Gate-Source Charge		Q <sub>gs</sub>	-	93.6	-	nC	$V_{GS} = 4.5V, V_{DS} = 10V,$ $V_{DS} = 250 \text{mA}$
Gate-Drain Charge		Q <sub>gd</sub>	-	116.6	-	nC	I <sub>D</sub> = 250IIIA
Turn-On Delay Time		t <sub>D(on)</sub>	-	5.1	-	ns	
Turn-On Rise Time		t <sub>r</sub>	-	7.4	-	ns	V <sub>DD</sub> = 10V, V <sub>GS</sub> = 4.5V,
Turn-Off Delay Time		t <sub>D(off)</sub>	-	26.7	-	ns	$R_L = 47\Omega$ , $R_G = 10\Omega$ ,
Turn-Off Fall Time		t <sub>f</sub>	-	12.3	-	ns	7

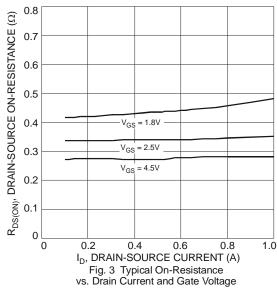
Notes: 5. Short duration pulse test used to minimize self-heating effect.

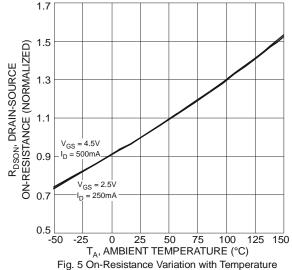
6. Guaranteed by design. Not subject to production testing.

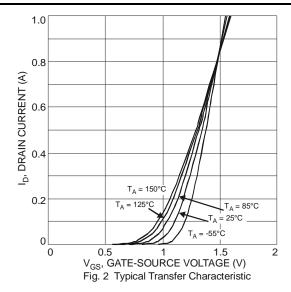


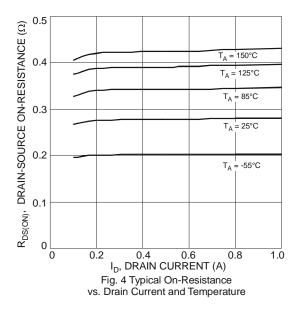
## N-CHANNEL - Q1

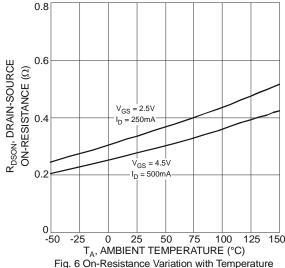














# N-CHANNEL - Q1 (continued)

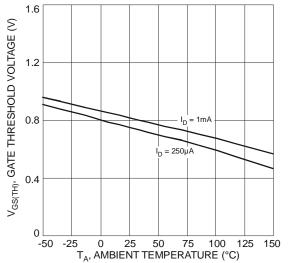
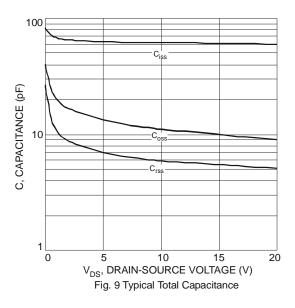
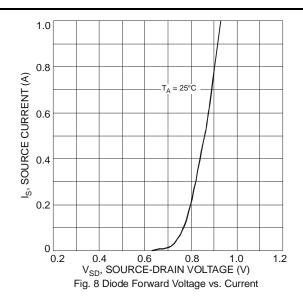


Fig. 7 Gate Threshold Variation vs. Ambient Temperature





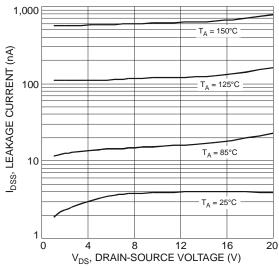


Fig. 10 Typical Leakage Current vs. Drain-Source Voltage

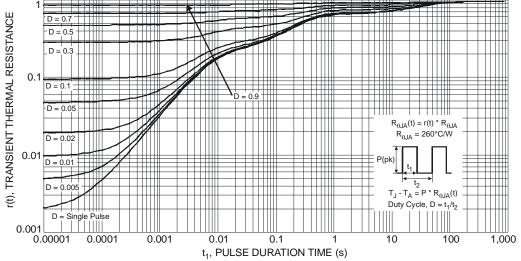


Fig. 11 Transient Thermal Response



# Electrical Characteristics P-CHANNEL – Q2@T<sub>A</sub> = 25°C unless otherwise specified

Characteristic		Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 5)							
Drain-Source Breakdown Voltage		BV <sub>DSS</sub>	-20	-	-	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	$@T_c = 25^{\circ}C$	I <sub>DSS</sub>	ı	-	-100	nA	$V_{DS} = -20V, V_{GS} = 0V$
Gate-Source Leakage		$I_{GSS}$	-	-	±2.0	μA	$V_{GS} = \pm 4.5 V, V_{DS} = 0 V$
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage		$V_{GS(th)}$	-0.5	-	-1.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
				0.5	0.75		$V_{GS} = -4.5V, I_D = -430mA$
Static Drain-Source On-Resistance		R <sub>DS (ON)</sub>	-	0.7	1.05	Ω	$V_{GS} = -2.5V, I_D = -300mA$
				1.0	1.5		$V_{GS} = -1.8V, I_D = -150mA$
Forward Transfer Admittance		Y <sub>fs</sub>	-	0.9	-	S	$V_{DS} = -10V, I_D = -250mA$
Diode Forward Voltage (Note 5)		$V_{SD}$	-	-0.8	-1.2	V	$V_{GS} = 0V, I_{S} = -150mA$
DYNAMIC CHARACTERISTICS (Note 6)							
Input Capacitance		C <sub>iss</sub>	-	59.76	-	pF	101/1/
Output Capacitance		Coss	-	12.07	-	pF	$V_{DS} = -16V, V_{GS} = 0V,$ -f = 1.0MHz
Reverse Transfer Capacitance		C <sub>rss</sub>	-	6.36	-	pF	71 = 1.0IVII IZ
Total Gate Charge (4.5V)		Qg	-	622.4	-	рС	
Gate-Source Charge		Q <sub>gs</sub>	-	100.3	-	рC	$V_{GS} = -4.5V, V_{DS} = -10V,$
Gate-Drain Charge		$Q_{gd}$	-	132.2	-	рС	$I_D = -250 \text{mA}$
Turn-On Delay Time		t <sub>D(on)</sub>	-	5.1	-	ns	
Turn-On Rise Time		t <sub>r</sub>	-	8.1	-	ns	$V_{DS} = -10V, V_{GS} = -4.5V,$
Turn-Off Delay Time		t <sub>D(off)</sub>	-	28.4	-	ns	$R_G = 10\Omega$ , $R_L = 47\Omega$
Turn-Off Fall Time		t <sub>f</sub>	-	20.72	-	ns	7

Notes:

<sup>5.</sup> Short duration pulse test used to minimize self-heating effect.6. Guaranteed by design. Not subject to production testing



#### P-CHANNEL - Q2

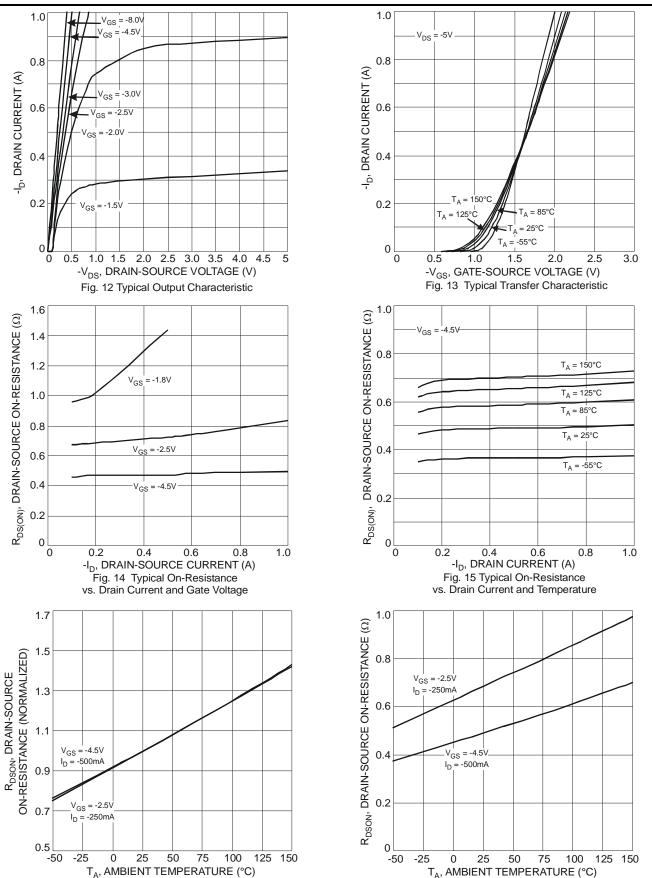


Fig. 16 On-Resistance Variation with Temperature

Fig. 17 On-Resistance Variation with Temperature



# P-CHANNEL - Q2 (continued)

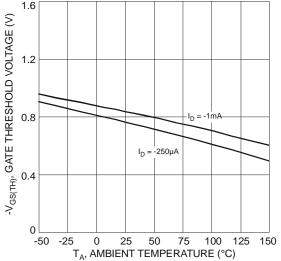
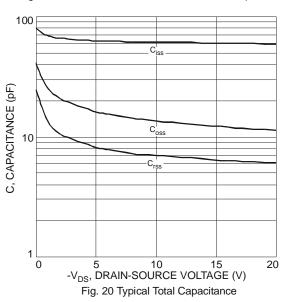
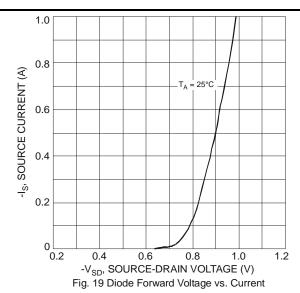
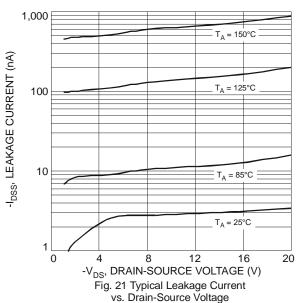


Fig. 18 Gate Threshold Variation vs. Ambient Temperature







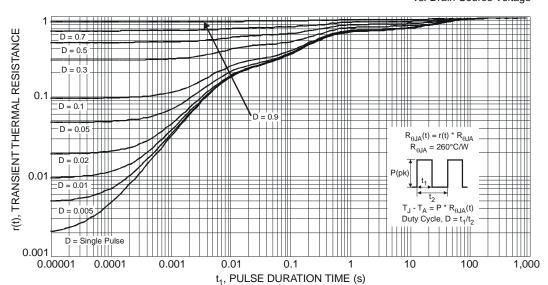
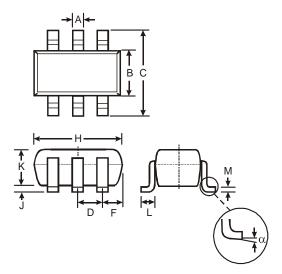


Fig. 22 Transient Thermal Response

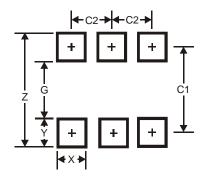


# **Package Outline Dimensions**



SOT-363					
Dim	Min	Max			
Α	0.10	0.30			
В	1.15	1.35			
C	2.00	2.20			
D	0.65	Тур			
F	0.40	0.45			
Н	1.80	2.20			
7	0	0.10			
K	0.90	1.00			
L	0.25	0.40			
M	0.10	0.22			
α	0°	8°			
All Dimensions in mm					

# **Suggested Pad Layout**



Dimensions	Value (in mm)
Z	2.5
G	1.3
Х	0.42
Y	0.6
C1	1.9
C2	0.65



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